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Derrick Brown

**ATTN: PATENT APPLICATION**

Commissioner for Patents  
Washington, D.C. 20231

Re: U.S. Patent Application Entitled "**METHODS AND SYSTEMS FOR DETERMINING A PRESENCE OF MACRO AND MICRO DEFECTS ON A SPECIMEN**" – Levy, et al.

Sir:

Transmitted herewith for filing is a disclosure including a title page, a 273 page specification, 1131 pages of claims (Claims 1-6632), and a one page abstract. In addition, we have also included 27 formal drawings on 23 sheets. The disclosure and drawings constitute the application of Ady Levy, Kyle Brown, Rodney Smedt, Gary Bultman, Mehrdad Nikoonahad, Dan Wack, and John Fielden for the above-entitled invention.

This application claims priority to U.S. Provisional Application No. 60/234,323 entitled "METHODS AND SYSTEMS FOR SEMICONDUCTOR FABRICATION PROCESSES" filed September 20, 2000.

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Enclosures